



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of : **Confirmation No. 4508**  
Toshifumi KIMBA et al. : Docket No. 2000-1706A  
Serial No. 09/734,737 : Group Art Unit 2877  
Filed December 13, 2000 : Examiner Hoa Q. Pham

SUBSTRATE FILM THICKNESS  
MEASUREMENT METHOD, SUBSTRATE  
FILM THICKNESS MEASUREMENT  
APPARATUS AND SUBSTRATE  
PROCESSING APPARATUS

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RESPONSE

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the Restriction Requirement of August 8, 2003, Applicant hereby elects Species C without traverse for further prosecution. It is submitted that claims 29-33, 48-52 and 70-75 read on the elected species.

In view of the above election and amendments, a full examination on the merits of this application is respectfully requested.

Respectfully submitted,

Toshifumi KIMBA et al.

By: 

W. Douglas Hahn  
Registration No. 44,142  
Attorney for Applicants

WDH/gtg  
Washington, D.C. 20006-1021  
Telephone (202) 721-8200  
Facsimile (202) 721-8250  
August 29, 2003